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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	5900
Number of Logic Elements/Cells	75520
Total RAM Bits	3870720
Number of I/O	300
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	676-BGA
Supplier Device Package	676-FBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7a75t-1fgg676i

Table 2: Recommended Operating Conditions⁽¹⁾⁽²⁾ (Cont'd)

Symbol	Description	Min	Typ	Max	Units
Temperature					
T_j	Junction temperature operating range for commercial (C) temperature devices	0	—	85	°C
	Junction temperature operating range for extended (E) temperature devices	0	—	100	°C
	Junction temperature operating range for industrial (I) temperature devices	-40	—	100	°C

Notes:

1. All voltages are relative to ground.
2. For the design of the power distribution system consult [UG483, 7 Series FPGAs PCB Design and Pin Planning Guide](#).
3. Configuration data is retained even if V_{CCO} drops to 0V.
4. Includes V_{CCO} of 1.2V, 1.5V, 1.8V, 2.5V, and 3.3V.
5. The lower absolute voltage specification always applies.
6. A total of 200 mA per bank should not be exceeded.
7. V_{CCBATT} is required only when using bitstream encryption. If battery is not used, connect V_{CCBATT} to either ground or V_{CCAUX} .
8. Each voltage listed requires the filter circuit described in [UG482: 7 Series FPGAs GTP Transceiver User Guide](#).
9. Voltages are specified for the temperature range of $T_j = 0^\circ\text{C}$ to $+85^\circ\text{C}$.

Table 3: DC Characteristics Over Recommended Operating Conditions

Symbol	Description	Min	Typ ⁽¹⁾	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)	0.75	—	—	V
V_{DRI}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)	1.5	—	—	V
I_{REF}	V_{REF} leakage current per pin	—	—	15	μA
I_L	Input or output leakage current per pin (sample-tested)	—	—	15	μA
$C_{IN}^{(2)}$	Die input capacitance at the pad	—	—	8	pF
I_{RPU}	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 3.3\text{V}$	90	—	330	μA
	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 2.5\text{V}$	68	—	250	μA
	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 1.8\text{V}$	34	—	220	μA
	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 1.5\text{V}$	23	—	150	μA
	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 1.2\text{V}$	12	—	120	μA
I_{RPD}	Pad pull-down (when selected) @ $V_{IN} = 3.3\text{V}$	68	—	330	μA
	Pad pull-down (when selected) @ $V_{IN} = 1.8\text{V}$	45	—	180	μA
I_{CCADC}	Analog supply current, analog circuits in powered up state	—	—	25	mA
$I_{BATT}^{(3)}$	Battery supply current	—	—	150	nA
$R_{IN_TERM}^{(4)}$	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ (UNTUNED_SPLIT_40) for commercial (C), and industrial (I), and extended (E) temperature devices	28	40	55	Ω
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ (UNTUNED_SPLIT_50) for commercial (C), and industrial (I), and extended (E) temperature devices	35	50	65	Ω
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ (UNTUNED_SPLIT_60) for commercial (C), and industrial (I), and extended (E) temperature devices	44	60	83	Ω

Power-On/Off Power Supply Sequencing

The recommended power-on sequence is V_{CCINT} , V_{CCBRAM} , V_{CCAUX} , and V_{CCO} to achieve minimum current draw and ensure that the I/Os are 3-stated at power-on. The recommended power-off sequence is the reverse of the power-on sequence. If V_{CCINT} and V_{CCBRAM} have the same recommended voltage levels then both can be powered by the same supply and ramped simultaneously. If V_{CCAUX} and V_{CCO} have the same recommended voltage levels then both can be powered by the same supply and ramped simultaneously.

For V_{CCO} voltages of 3.3V in HR I/O banks and configuration bank 0:

- The voltage difference between V_{CCO} and V_{CCAUX} must not exceed 2.625V for longer than $T_{VCCO2VCCAUX}$ for each power-on/off cycle to maintain device reliability levels.
- The $T_{VCCO2VCCAUX}$ time can be allocated in any percentage between the power-on and power-off ramps.

The recommended power-on sequence to achieve minimum current draw for the GTP transceivers is V_{CCINT} , $V_{MGTAVCC}$, $V_{MGTAVTT}$ OR $V_{MGTAVCC}$, V_{CCINT} , $V_{MGTAVTT}$. There is no recommended sequencing for $V_{MGTAVCAUX}$. Both $V_{MGTAVCC}$ and V_{CCINT} can be ramped simultaneously. The recommended power-off sequence is the reverse of the power-on sequence to achieve minimum current draw.

If these recommended sequences are not met, current drawn from $V_{MGTAVTT}$ can be higher than specifications during power-up and power-down.

- When $V_{MGTAVTT}$ is powered before $V_{MGTAVCC}$ and $V_{MGTAVTT} - V_{MGTAVCC} > 150$ mV and $V_{MGTAVCC} < 0.7$ V, the $V_{MGTAVTT}$ current draw can increase by 460 mA per transceiver during $V_{MGTAVCC}$ ramp up. The duration of the current draw can be up to $0.3 \times T_{MGTAVCC}$ (ramp time from GND to 90% of $V_{MGTAVCC}$). The reverse is true for power-down.
- When $V_{MGTAVTT}$ is powered before V_{CCINT} and $V_{MGTAVTT} - V_{CCINT} > 150$ mV and $V_{CCINT} < 0.7$ V, the $V_{MGTAVTT}$ current draw can increase by 50 mA per transceiver during V_{CCINT} ramp up. The duration of the current draw can be up to $0.3 \times T_{VCCINT}$ (ramp time from GND to 90% of V_{CCINT}). The reverse is true for power-down.

Table 6 shows the minimum current, in addition to I_{CCQ} , that is required by Artix-7 devices for proper power-on and configuration. If the current minimums shown in **Table 5** and **Table 6** are met, the device powers on after all four supplies have passed through their power-on reset threshold voltages. The FPGA must not be configured until after V_{CCINT} is applied.

Once initialized and configured, use the Xilinx Power Estimator (XPE) tools to estimate current drain on these supplies.

Table 6: Power-On Current for Artix-7 Devices⁽¹⁾

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	I_{CCOMIN}	$I_{CCBRAMMIN}$	Units
	Typ ⁽²⁾	Typ ⁽²⁾	Typ ⁽²⁾	Typ ⁽²⁾	
XC7A100T	$I_{CCINTQ} + 170$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XC7A200T	$I_{CCINTQ} + 340$	$I_{CCAUXQ} + 50$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 80$	mA

Notes:

1. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.
2. Typical values are specified at nominal voltage, 25°C.

Table 7: Power Supply Ramp Time

Symbol	Description	Conditions	Min	Max	Units
T_{VCCINT}	Ramp time from GND to 90% of V_{CCINT}		0.2	50	ms
T_{VCCO}	Ramp time from GND to 90% of V_{CCO}		0.2	50	ms
T_{VCCAUX}	Ramp time from GND to 90% of V_{CCAUX}		0.2	50	ms
$T_{VCCBRAM}$	Ramp time from GND to 90% of V_{CCBRAM}		0.2	50	ms
$T_{VCCO2VCCAUX}$	Allowed time per power cycle for $V_{CCO} - V_{CCAUX} > 2.625V$	$T_J = 100^{\circ}\text{C}^{(1)}$	—	500	ms
		$T_J = 85^{\circ}\text{C}^{(1)}$	—	800	
$T_{MGTAVCC}$	Ramp time from GND to 90% of $V_{MGTAVCC}$		0.2	50	ms
$T_{MGTAVTT}$	Ramp time from GND to 90% of $V_{MGTAVTT}$		0.2	50	ms

Notes:

1. Based on 240,000 power cycles with nominal V_{CCO} of 3.3V or 36,500 power cycles with worst case V_{CCO} of 3.465V.

DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V_{CCO} with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Table 8: SelectIO DC Input and Output Levels⁽¹⁾⁽²⁾

I/O Standard	V_{IL}		V_{IH}		V_{OL}	V_{OH}	I_{OL}	I_{OH}
	V , Min	V , Max	V , Min	V , Max	V , Max	V , Min	mA, Max	mA, Min
HSTL_I	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	8.00	-8.00
HSTL_I_18	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	8.00	-8.00
HSTL_II	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	16.00	-16.00
HSTL_II_18	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	16.00	-16.00
HSUL_12	-0.300	$V_{REF} - 0.130$	$V_{REF} + 0.130$	$V_{CCO} + 0.300$	20% V_{CCO}	80% V_{CCO}	0.10	-0.10
LVCMOS12	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	Note 3	Note 3
LVCMOS15	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	25% V_{CCO}	75% V_{CCO}	Note 4	Note 4
LVCMOS18	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	0.450	$V_{CCO} - 0.450$	Note 5	Note 5
LVCMOS25	-0.300	0.7	1.700	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	Note 4	Note 4
LVCMOS33	-0.300	0.8	2.000	3.450	0.400	$V_{CCO} - 0.400$	Note 4	Note 4
LVTTL	-0.300	0.8	2.000	3.450	0.400	2.400	Note 5	Note 5
MOBILE_DDR	-0.300	20% V_{CCO}	80% V_{CCO}	$V_{CCO} + 0.300$	10% V_{CCO}	90% V_{CCO}	0.10	-0.10
PCI33_3	-0.500	30% V_{CCO}	50% V_{CCO}	$V_{CCO} + 0.500$	10% V_{CCO}	90% V_{CCO}	1.50	-0.50
SSTL135	-0.300	$V_{REF} - 0.090$	$V_{REF} + 0.090$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.150$	$V_{CCO}/2 + 0.150$	13.00	-13.00
SSTL135_R	-0.300	$V_{REF} - 0.090$	$V_{REF} + 0.090$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.150$	$V_{CCO}/2 + 0.150$	8.90	-8.90
SSTL15	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.175$	$V_{CCO}/2 + 0.175$	13.00	-13.00
SSTL15_R	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.175$	$V_{CCO}/2 + 0.175$	8.90	-8.90
SSTL18_I	-0.300	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.470$	$V_{CCO}/2 + 0.470$	8.00	-8.00
SSTL18_II	-0.300	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.600$	$V_{CCO}/2 + 0.600$	13.40	-13.40

Notes:

- Tested according to relevant specifications.
- 3.3V and 2.5V standards are only supported in 3.3V I/O banks.
- Supported drive strengths of 4, 8, or 12 mA in HR I/O banks.
- Supported drive strengths of 4, 8, 12, or 16 mA in HR I/O banks.
- Supported drive strengths of 4, 8, 12, 16, or 24 mA in HR I/O banks.
- For detailed interface specific DC voltage levels, see [UG471: 7 Series FPGAs SelectIO Resources User Guide](#).

Table 9: Differential SelectIO DC Input and Output Levels

I/O Standard	V _{ICM} ⁽¹⁾			V _{ID} ⁽²⁾			V _{OCM} ⁽³⁾			V _{OD} ⁽⁴⁾		
	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max
BLVDS_25	0.300	1.200	1.425	0.100	—	—	—	1.250	—	Note 5		
MINI_LVDS_25	0.300	1.200	V _{CCAUX}	0.200	0.400	0.600	1.000	1.200	1.400	0.300	0.450	0.600
PPDS_25	0.200	0.900	V _{CCAUX}	0.100	0.250	0.400	0.500	0.950	1.400	0.100	0.250	0.400
RSDS_25	0.300	0.900	1.500	0.100	0.350	0.600	1.000	1.200	1.400	0.100	0.350	0.600
TMDS_33	2.700	2.965	3.230	0.150	0.675	1.200	V _{CCO} –0.405	V _{CCO} –0.300	V _{CCO} –0.190	0.400	0.600	0.800

Notes:

1. V_{ICM} is the input common mode voltage.
2. V_{ID} is the input differential voltage (Q – \bar{Q}).
3. V_{OCM} is the output common mode voltage.
4. V_{OD} is the output differential voltage (Q – \bar{Q}).
5. V_{OD} for BLVDS will vary significantly depending on topology and loading.

Table 10: Complementary Differential SelectIO DC Input and Output Levels

I/O Standard	V _{ICM} ⁽¹⁾			V _{ID} ⁽²⁾		V _{OL} ⁽³⁾		V _{OH} ⁽⁴⁾		I _{OL}	I _{OH}
	V, Min	V, Typ	V, Max	V, Min	V, Max	V, Max	V, Min	mA, Max	mA, Min		
DIFF_HSTL_I	0.300	0.750	1.125	0.100	—	0.400	V _{CCO} –0.400	8.00	–8.00		
DIFF_HSTL_I_18	0.300	0.900	1.425	0.100	—	0.400	V _{CCO} –0.400	8.00	–8.00		
DIFF_HSTL_II	0.300	0.750	1.125	0.100	—	0.400	V _{CCO} –0.400	16.00	–16.00		
DIFF_HSTL_II_18	0.300	0.900	1.425	0.100	—	0.400	V _{CCO} –0.400	16.00	–16.00		
DIFF_HSUL_12	0.300	0.600	0.850	0.100	—	20% V _{CCO}	80% V _{CCO}	0.100	–0.100		
DIFF_MOBILE_DDR	0.300	0.900	1.425	0.100	—	10% V _{CCO}	90% V _{CCO}	0.100	–0.100		
DIFF_SSTL135	0.300	0.675	1.000	0.100	—	(V _{CCO} /2) – 0.150	(V _{CCO} /2) + 0.150	13.0	–13.0		
DIFF_SSTL135_R	0.300	0.675	1.000	0.100	—	(V _{CCO} /2) – 0.150	(V _{CCO} /2) + 0.150	8.9	–8.9		
DIFF_SSTL15	0.300	0.750	1.125	0.100	—	(V _{CCO} /2) – 0.175	(V _{CCO} /2) + 0.175	13.0	–13.0		
DIFF_SSTL15_R	0.300	0.750	1.125	0.100	—	(V _{CCO} /2) – 0.175	(V _{CCO} /2) + 0.175	8.9	–8.9		
DIFF_SSTL18_I	0.300	0.900	1.425	0.100	—	(V _{CCO} /2) – 0.470	(V _{CCO} /2) + 0.470	8.00	–8.00		
DIFF_SSTL18_II	0.300	0.900	1.425	0.100	—	(V _{CCO} /2) – 0.600	(V _{CCO} /2) + 0.600	13.4	–13.4		

Notes:

1. V_{ICM} is the input common mode voltage.
2. V_{ID} is the input differential voltage (Q – \bar{Q}).
3. V_{OL} is the single-ended low-output voltage.
4. V_{OH} is the single-ended high-output voltage.

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Artix-7 devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [AC Switching Characteristics, page 9](#).

Table 14: Networking Applications Interface Performances

Description	Speed Grade				Units	
	1.0V		0.9V			
	-3	-2/-2L	-1	-2L		
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	680	680	600	600	Mb/s	
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 14)	1250	1250	950	950	Mb/s	
SDR LVDS receiver (SFI-4.1) ⁽¹⁾	680	680	600	600	Mb/s	
DDR LVDS receiver (SPI-4.2) ⁽¹⁾	1250	1250	950	950	Mb/s	

Notes:

- LVDS receivers are typically bounded with certain applications where specific dynamic phase-alignment (DPA) algorithms dominate deterministic performance.

Table 15: Maximum Physical Interface (PHY) Rate for Memory Interfaces⁽¹⁾⁽²⁾

Memory Standard	Speed Grade				Units	
	1.0V		0.9V			
	-3	-2/-2L	-1	-2L		
4:1 Memory Controllers						
DDR3	1066	800	800	800	Mb/s	
DDR3L	800	800	667	667	Mb/s	
DDR2	800	800	667	667	Mb/s	
LPDDR2	667	667	533	533	Mb/s	
2:1 Memory Controllers						
DDR3	800	700	620	620	Mb/s	
DDR3L	800	700	620	620	Mb/s	
DDR2	800	700	620	620	Mb/s	

Notes:

- V_{REF} tracking is required. For more information, see [UG586, 7 Series FPGAs Memory Interface Solutions User Guide](#).
- When using the internal V_{REF} the maximum data rate is 800 Mb/s (400 MHz).

Output Serializer/Deserializer Switching Characteristics

Table 21: OSERDES Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T _{OSDCK_D} /T _{OSCKD_D}	D input setup/hold with respect to CLKDIV	0.42/0.03	0.45/0.03	0.63/0.03	0.44/-0.25	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input setup/hold with respect to CLK	0.69/-0.13	0.73/-0.13	0.88/-0.13	0.60/-0.25	ns
T _{OSDCK_T2} /T _{OSCKD_T2} ⁽¹⁾	T input setup/hold with respect to CLKDIV	0.31/-0.13	0.34/-0.13	0.39/-0.13	0.46/-0.25	ns
T _{oscck_oce} /T _{osckc_oce}	OCE input setup/hold with respect to CLK	0.32/0.58	0.34/0.58	0.51/0.58	0.21/-0.15	ns
T _{oscck_s}	SR (reset) input setup with respect to CLKDIV	0.47	0.52	0.85	0.70	ns
T _{oscck_tce} /T _{osckc_tce}	TCE input setup/hold with respect to CLK	0.32/0.01	0.34/0.01	0.51/0.01	0.22/-0.15	ns
Sequential Delays						
T _{oscko_oq}	Clock to out from CLK to OQ	0.40	0.42	0.48	0.54	ns
T _{oscko_tq}	Clock to out from CLK to TQ	0.47	0.49	0.56	0.63	ns
Combinatorial						
T _{osdo_ttq}	T input to TQ Out	0.83	0.92	1.11	1.18	ns

Notes:

- T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in TRACE report.

CLB Switching Characteristics

Table 24: CLB Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Combinatorial Delays						
T _{ILO}	An – Dn LUT address to A	0.10	0.11	0.13	0.15	ns, Max
T _{ILO_2}	An – Dn LUT address to AMUX/CMUX	0.27	0.30	0.36	0.41	ns, Max
T _{ILO_3}	An – Dn LUT address to BMUX_A	0.42	0.46	0.55	0.65	ns, Max
T _{I TO}	An – Dn inputs to A – D Q outputs	0.94	1.05	1.27	1.51	ns, Max
T _{AXA}	AX inputs to AMUX output	0.62	0.69	0.84	1.01	ns, Max
T _{AXB}	AX inputs to BMUX output	0.58	0.66	0.83	0.98	ns, Max
T _{AXC}	AX inputs to CMUX output	0.60	0.68	0.82	0.98	ns, Max
T _{AXD}	AX inputs to DMUX output	0.68	0.75	0.90	1.08	ns, Max
T _{BXB}	BX inputs to BMUX output	0.51	0.57	0.69	0.82	ns, Max
T _{BXD}	BX inputs to DMUX output	0.62	0.69	0.82	0.99	ns, Max
T _{CXC}	CX inputs to CMUX output	0.42	0.48	0.58	0.69	ns, Max
T _{CXD}	CX inputs to DMUX output	0.53	0.59	0.71	0.86	ns, Max
T _{DXD}	DX inputs to DMUX output	0.52	0.58	0.70	0.84	ns, Max
Sequential Delays						
T _{CKO}	Clock to AQ – DQ outputs	0.40	0.44	0.53	0.62	ns, Max
T _{SHCKO}	Clock to AMUX – DMUX outputs	0.47	0.53	0.66	0.73	ns, Max
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK						
T _{AS/T_{AH}}	A _N – D _N input to CLK on A – D flip-flops	0.07/0.12	0.09/0.14	0.11/0.18	0.11/0.20	ns, Min
T _{DICK/T_{CKDI}}	A _X – D _X input to CLK on A – D flip-flops	0.06/0.19	0.07/0.21	0.09/0.26	0.09/0.31	ns, Min
	A _X – D _X input through MUXs and/or carry logic to CLK on A – D flip-flops	0.59/0.08	0.66/0.09	0.81/0.11	0.97/0.12	ns, Min
T _{CECK_CLB/} T _{CKCE_CLB}	CE input to CLK on A – D flip-flops	0.15/0.00	0.17/0.00	0.21/0.01	0.34/–0.01	ns, Min
T _{SRCK/T_{CKSR}}	SR input to CLK on A – D flip-flops	0.38/0.03	0.43/0.04	0.53/0.05	0.62/0.05	ns, Min
Set/Reset						
T _{SRMIN}	SR input minimum pulse width	0.52	0.78	1.04	0.95	ns, Min
T _{RQ}	Delay from SR input to AQ – DQ flip-flops	0.53	0.59	0.71	0.83	ns, Max
T _{CEO}	Delay from CE input to AQ – DQ flip-flops	0.52	0.58	0.70	0.83	ns, Max
F _{TOG}	Toggle frequency (for export control)	1412	1286	1098	1098	MHz

Table 27: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T _{RCKC_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.32/0.42	0.34/0.43	0.36/0.46	0.40/0.47	ns, Min
T _{RCKC_WEA} /T _{RCKC_WEA}	Write enable (WE) input (block RAM only)	0.44/0.18	0.48/0.19	0.54/0.20	0.64/0.23	ns, Min
T _{RCKC_WREN} /T _{RCKC_WREN}	WREN FIFO inputs	0.46/0.30	0.46/0.35	0.47/0.43	0.77/0.44	ns, Min
T _{RCKC_RDEN} /T _{RCKC_RDEN}	RDEN FIFO inputs	0.42/0.30	0.43/0.35	0.43/0.43	0.71/0.44	ns, Min
Reset Delays						
T _{RCO_FLAGS}	Reset RST to FIFO flags/pointers ⁽¹⁰⁾	0.90	0.98	1.10	1.25	ns, Max
T _{RREC_RST} /T _{RREM_RST}	FIFO reset recovery and removal timing ⁽¹¹⁾	1.87/-0.81	2.07/-0.81	2.37/-0.81	2.44/-0.71	ns, Max
Maximum Frequency						
F _{MAX_BRAM_WF_NC}	Block RAM (write first and no change modes) when not in SDP RF mode	509.68	460.83	388.20	315.66	MHz
F _{MAX_BRAM_RF_PERFORMANCE}	Block RAM (read first, performance mode) when in SDP RF mode but no address overlap between port A and port B	509.68	460.83	388.20	315.66	MHz
F _{MAX_BRAM_RF_DELAYED_WRITE}	Block RAM (read first, delayed write mode) when in SDP RF mode and there is possibility of overlap between port A and port B addresses	447.63	404.53	339.67	268.96	MHz
F _{MAX_CAS_WF_NC}	Block RAM cascade (write first, no change mode) when cascade but not in RF mode	467.07	418.59	345.78	273.30	MHz
F _{MAX_CAS_RF_PERFORMANCE}	Block RAM cascade (read first, performance mode) when in cascade with RF mode and no possibility of address overlap/one port is disabled	467.07	418.59	345.78	273.30	MHz
F _{MAX_CAS_RF_DELAYED_WRITE}	When in cascade RF mode and there is a possibility of address overlap between port A and port B	405.35	362.19	297.35	226.60	MHz
F _{MAX_FIFO}	FIFO in all modes without ECC	509.68	460.83	388.20	315.66	MHz
F _{MAX_ECC}	Block RAM and FIFO in ECC configuration	410.34	365.10	297.53	215.38	MHz

Notes:

1. TRACE will report all of these parameters as T_{RCKO_DO}.
2. T_{RCKO_DOR} includes T_{RCKO_DOW}, T_{RCKO_DOPR}, and T_{RCKO_DOPW} as well as the B port equivalent timing parameters.
3. These parameters also apply to synchronous FIFO with DO_REG = 0.
4. T_{RCKO_DO} includes T_{RCKO_DOP} as well as the B port equivalent timing parameters.
5. These parameters also apply to multirate (asynchronous) and synchronous FIFO with DO_REG = 1.
6. T_{RCKO_FLAGS} includes the following parameters: T_{RCKO_AEMPTY}, T_{RCKO_AFULL}, T_{RCKO_EMPTY}, T_{RCKO_FULL}, T_{RCKO_RDERR}, T_{RCKO_WRERR}.
7. T_{RCKO_POINTERS} includes both T_{RCKO_RDCOUNT} and T_{RCKO_WRCOUNT}.
8. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
9. These parameters include both A and B inputs as well as the parity inputs of A and B.
10. T_{RCO_FLAGS} includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
11. RDEN and WREN must be held Low prior to and during reset. The FIFO reset must be asserted for at least five positive clock edges of the slowest clock (WRCLK or RDCLK).

DSP48E1 Switching Characteristics

Table 28: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock						
T _{DSPDCK_A_AREG} /T _{DSPCKD_A_AREG}	A input to A register CLK	0.26/ 0.12	0.30/ 0.13	0.37/ 0.14	0.45/ 0.14	ns
T _{DSPDCK_B_BREG} /T _{DSPCKD_B_BREG}	B input to B register CLK	0.33/ 0.15	0.38/ 0.16	0.45/ 0.18	0.60/ 0.19	ns
T _{DSPDCK_C_CREG} /T _{DSPCKD_C_CREG}	C input to C register CLK	0.17/ 0.17	0.20/ 0.19	0.24/ 0.21	0.34/ 0.29	ns
T _{DSPDCK_D_DREG} /T _{DSPCKD_D_DREG}	D input to D register CLK	0.25/ 0.25	0.32/ 0.27	0.42/ 0.27	0.54/ 0.23	ns
T _{DSPDCK_ACIN_AREG} /T _{DSPCKD_ACIN_AREG}	ACIN input to A register CLK	0.23/ 0.12	0.27/ 0.13	0.32/ 0.14	0.36/ 0.14	ns
T _{DSPDCK_BCIN_BREG} /T _{DSPCKD_BCIN_BREG}	BCIN input to B register CLK	0.25/ 0.15	0.29/ 0.16	0.36/ 0.18	0.41/ 0.19	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock						
T _{DSPDCK_{A,B}_MREG_MULT} / T _{DSPCKD_B_MREG_MULT}	{A, B} input to M register CLK using multiplier	2.40/ -0.01	2.76/ -0.01	3.29/ -0.01	4.31/ -0.07	ns
T _{DSPDCK_{A,B}_ADREG} /T _{DSPCKD_D_ADREG}	{A, D} input to AD register CLK	1.29/ -0.02	1.48/ -0.02	1.76/ -0.02	2.29/ -0.27	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock						
T _{DSPDCK_{A,B}_PREG_MULT} / T _{DSPCKD_{A,B}_PREG_MULT}	{A, B} input to P register CLK using multiplier	4.02/ -0.28	4.60/ -0.28	5.48/ -0.28	6.95/ -0.48	ns
T _{DSPDCK_D_PREG_MULT} / T _{DSPCKD_D_PREG_MULT}	D input to P register CLK using multiplier	3.93/ -0.73	4.50/ -0.73	5.35/ -0.73	6.73/ -1.68	ns
T _{DSPDCK_{A,B}_PREG} / T _{DSPCKD_{A,B}_PREG}	A or B input to P register CLK not using multiplier	1.73/ -0.28	1.98/ -0.28	2.35/ -0.28	2.80/ -0.48	ns
T _{DSPDCK_C_PREG} / T _{DSPCKD_C_PREG}	C input to P register CLK not using multiplier	1.54/ -0.26	1.76/ -0.26	2.10/ -0.26	2.54/ -0.45	ns
T _{DSPDCK_PCIN_PREG} / T _{DSPCKD_PCIN_PREG}	PCIN input to P register CLK	1.32/ -0.15	1.51/ -0.15	1.80/ -0.15	2.13/ -0.25	ns
Setup and Hold Times of the CE Pins						
T _{DSPDCK_{CEA;CEB}_{AREG;BREG}} / T _{DSPCKD_{CEA;CEB}_{AREG;BREG}}	{CEA; CEB} input to {A; B} register CLK	0.35/ 0.06	0.42/ 0.08	0.52/ 0.11	0.64/ 0.11	ns
T _{DSPDCK_CEC_CREG} /T _{DSPCKD_CEC_CREG}	CEC input to C register CLK	0.28/ 0.10	0.34/ 0.11	0.42/ 0.13	0.49/ 0.16	ns
T _{DSPDCK_CED_DREG} /T _{DSPCKD_CED_DREG}	CED input to D register CLK	0.36/ -0.03	0.43/ -0.03	0.52/ -0.03	0.68/ 0.14	ns
T _{DSPDCK_CEM_MREG} /T _{DSPCKD_CEM_MREG}	CEM input to M register CLK	0.17/ 0.18	0.21/ 0.20	0.27/ 0.23	0.45/ 0.29	ns
T _{DSPDCK_CEP_PREG} /T _{DSPCKD_CEP_PREG}	CEP input to P register CLK	0.36/ 0.01	0.43/ 0.01	0.53/ 0.01	0.63/ 0.00	ns

Clock Buffers and Networks

Table 29: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BCCCK_CE/T_BCCKC_CE ⁽¹⁾	CE pins setup/hold	0.12/0.39	0.13/0.40	0.16/0.41	0.31/0.17	ns
T_BCCCK_S/T_BCCKC_S ⁽¹⁾	S pins setup/hold	0.12/0.39	0.13/0.40	0.16/0.41	0.31/0.17	ns
T_BGCKO_O ⁽²⁾	BUFGCTRL delay from I0/I1 to O	0.08	0.09	0.10	0.14	ns
Maximum Frequency						
F _{MAX_BUFG}	Global clock tree (BUFG)	628.00	628.00	464.00	394.00	MHz

Notes:

1. T_{BCCCK_CE} and T_{BCCKC_CE} must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. T_{BGCKO_O} (BUFG delay from I0 to O) values are the same as T_{BCCKO_O} values.

Table 30: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BLOCKO_O	Clock to out delay from I to O	1.11	1.26	1.54	1.56	ns
Maximum Frequency						
F _{MAX_BUFIO}	I/O clock tree (BUFIO)	680.00	680.00	600.00	600.00	MHz

Table 31: Regional Clock Buffer Switching Characteristics (BUFR)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BRCKO_O	Clock to out delay from I to O	0.64	0.76	0.99	1.24	ns
T_BRCKO_O_BYP	Clock to out delay from I to O with Divide Bypass attribute set	0.34	0.39	0.52	0.72	ns
T_BRDO_O	Propagation delay from CLR to O	0.81	0.85	1.09	0.96	ns
Maximum Frequency						
F _{MAX_BUFR} ⁽¹⁾	Regional clock tree (BUFR)	420.00	375.00	315.00	315.00	MHz

Notes:

1. The maximum input frequency to the BUFR and BUFMR is the BUFIO F_{MAX} frequency.

Table 32: Horizontal Clock Buffer Switching Characteristics (BUFH)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BHCKO_O	BUFH delay from I to O	0.10	0.11	0.13	0.16	ns
T_BHCKC_CE/T_BHCKC_CE	CE pin setup and hold	0.19/0.13	0.22/0.15	0.28/0.21	0.35/0.08	ns
Maximum Frequency						
F_MAX_BUHF	Horizontal clock buffer (BUFH)	628.00	628.00	464.00	394.00	MHz

Table 33: Duty Cycle Distortion and Clock-Tree Skew

Symbol	Description	Device	Speed Grade				Units
			1.0V		0.9V		
			-3	-2/-2L	-1	-2L	
T_DCD_CLK	Global clock tree duty-cycle distortion ⁽¹⁾	All	0.20	0.20	0.20	0.25	ns
T_CKSKEW	Global clock tree skew ⁽²⁾	XC7A100T	0.27	0.33	0.36	0.48	ns
		XC7A200T	0.40	0.48	0.54	0.69	ns
T_DCD_BUFIO	I/O clock tree duty cycle distortion	All	0.14	0.14	0.14	0.14	ns
T_BUFIOSKEW	I/O clock tree skew across one clock region	All	0.03	0.03	0.03	0.03	ns
T_DCD_BUFR	Regional clock tree duty cycle distortion	All	0.18	0.18	0.18	0.18	ns

Notes:

- These parameters represent the worst-case duty cycle distortion observable at the I/O flip flops. For all I/O standards, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
- The T_CKSKEW value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx FPGA_Editor and Timing Analyzer tools to evaluate clock skew specific to your application.

MMCM Switching Characteristics

Table 34: MMCM Specification

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
MMCM_F_INMAX	Maximum input clock frequency	800.00	800.00	800.00	800.00	MHz
MMCM_F_INMIN	Minimum input clock frequency	10.00	10.00	10.00	10.00	MHz
MMCM_F_INJITTER	Maximum input clock period jitter	< 20% of clock input period or 1 ns Max				
MMCM_F_INDUTY	Allowable input duty cycle: 10—49 MHz	25	25	25	25	%
	Allowable input duty cycle: 50—199 MHz	30	30	30	30	%
	Allowable input duty cycle: 200—399 MHz	35	35	35	35	%
	Allowable input duty cycle: 400—499 MHz	40	40	40	40	%
	Allowable input duty cycle: >500 MHz	45	45	45	45	%
MMCM_F_MIN_PSCLK	Minimum dynamic phase-shift clock frequency	0.01	0.01	0.01	0.01	MHz
MMCM_F_MAX_PSCLK	Maximum dynamic phase-shift clock frequency	550.00	500.00	450.00	450.00	MHz
MMCM_F_VCOMIN	Minimum MMCM VCO frequency	600.00	600.00	600.00	600.00	MHz
MMCM_F_VCOMAX	Maximum MMCM VCO frequency	1600.00	1440.00	1200.00	1200.00	MHz

Table 34: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
MMCM_F_BANDWIDTH	Low MMCM bandwidth at typical ⁽¹⁾	1.00	1.00	1.00	1.00	MHz
	High MMCM bandwidth at typical ⁽¹⁾	4.00	4.00	4.00	4.00	MHz
MMCM_T_STATPHAOFFSET	Static phase offset of the MMCM outputs ⁽²⁾	0.12	0.12	0.12	0.12	ns
MMCM_T_OUTJITTER	MMCM output jitter	Note 3				
MMCM_T_OUTDUTY	MMCM output clock duty-cycle precision ⁽⁴⁾	0.20	0.20	0.20	0.25	ns
MMCM_T_LOCKMAX	MMCM maximum lock time	100.00	100.00	100.00	100.00	μs
MMCM_F_OUTMAX	MMCM maximum output frequency	800.00	800.00	800.00	800.00	MHz
MMCM_F_OUTMIN	MMCM minimum output frequency ⁽⁵⁾⁽⁶⁾	4.69	4.69	4.69	4.69	MHz
MMCM_T_EXTFDVAR	External clock feedback variation	< 20% of clock input period or 1 ns Max				
MMCM_RST_MINPULSE	Minimum reset pulse width	5.00	5.00	5.00	5.00	ns
MMCM_F_PFDMAX	Maximum frequency at the phase frequency detector	550.00	500.00	450.00	450.00	MHz
MMCM_F_PFDMIN	Minimum frequency at the phase frequency detector	10.00	10.00	10.00	10.00	MHz
MMCM_T_FBDelay	Maximum delay in the feedback path	3 ns Max or one CLKIN cycle				
MMCM Switching Characteristics Setup and Hold						
T_MMCM_DCK_PSEN/ T_MMCM_CKD_PSEN	Setup and hold of phase-shift enable	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
T_MMCM_DCK_PSINCDEC/ T_MMCM_CKD_PSINCDEC	Setup and hold of phase-shift increment/decrement	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
T_MMCM_CKO_PSDONE	Phase shift clock-to-out of PSDONE	0.59	0.68	0.81	0.78	ns
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
T_MMCM_DCK_DADDR/ T_MMCM_CKD_DADDR	DADDR setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_MMCM_DCK_DI/ T_MMCM_CKD_DI	DI setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_MMCM_DCK_DEN/ T_MMCM_CKD_DEN	DEN setup/hold	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
T_MMCM_DCK_DWE/ T_MMCM_CKD_DWE	DWE setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_MMCM_CKO_DRDY	CLK to out of DRDY	0.65	0.72	0.99	0.70	ns, Max
F_DCK	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

Notes:

- The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
- The static offset is measured between any MMCM outputs with identical phase.
- Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
- Includes global clock buffer.
- Calculated as $F_{VCO}/128$ assuming output duty cycle is 50%.
- When CLKOUT4_CASCADE = TRUE, MMCM_F_OUTMIN is 0.036 MHz.

PLL Switching Characteristics

Table 35: PLL Specification

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
PLL_F _{INMAX}	Maximum input clock frequency	800.00	800.00	800.00	800.00	MHz
PLL_F _{INMIN}	Minimum input clock frequency	19.00	19.00	19.00	19.00	MHz
PLL_F _{INJITTER}	Maximum input clock period jitter	< 20% of clock input period or 1 ns Max				
PLL_F _{INDUTY}	Allowable input duty cycle: 19—49 MHz	25	25	25	25	%
	Allowable input duty cycle: 50—199 MHz	30	30	30	30	%
	Allowable input duty cycle: 200—399 MHz	35	35	35	35	%
	Allowable input duty cycle: 400—499 MHz	40	40	40	40	%
	Allowable input duty cycle: >500 MHz	45	45	45	45	%
PLL_F _{VCOMIN}	Minimum PLL VCO frequency	800.00	800.00	800.00	800.00	MHz
PLL_F _{VCOMAX}	Maximum PLL VCO frequency	2133.00	1866.00	1600.00	1600.00	MHz
PLL_F _{BANDWIDTH}	Low PLL bandwidth at typical ⁽¹⁾	1.00	1.00	1.00	1.00	MHz
	High PLL bandwidth at typical ⁽¹⁾	4.00	4.00	4.00	4.00	MHz
PLL_T _{STATPHAOFFSET}	Static phase offset of the PLL outputs ⁽²⁾	0.12	0.12	0.12	0.12	ns
PLL_T _{OUTJITTER}	PLL output jitter	Note 3				
PLL_T _{OUTDUTY}	PLL output clock duty-cycle precision ⁽⁴⁾	0.20	0.20	0.20	0.25	ns
PLL_T _{LOCKMAX}	PLL maximum lock time	100.00	100.00	100.00	100.00	μs
PLL_F _{OUTMAX}	PLL maximum output frequency	800.00	800.00	800.00	800.00	MHz
PLL_F _{OUTMIN}	PLL minimum output frequency ⁽⁵⁾	6.25	6.25	6.25	6.25	MHz
PLL_T _{EXTFDVAR}	External clock feedback variation	< 20% of clock input period or 1 ns Max				
PLL_RST _{MINPULSE}	Minimum reset pulse width	5.00	5.00	5.00	5.00	ns
PLL_F _{PFDMAX}	Maximum frequency at the phase frequency detector	550.00	500.00	450.00	450.00	MHz
PLL_F _{PFDMIN}	Minimum frequency at the phase frequency detector	19.00	19.00	19.00	19.00	MHz
PLL_T _{FBDELAY}	Maximum delay in the feedback path	3 ns Max or one CLKIN cycle				

Dynamic Reconfiguration Port (DRP) for PLL Before and After DCLK

T _{PLLDCK_DADDR} /T _{PLLCKD_DADDR}	Setup and hold of D address	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{PLLDCK_DI} /T _{PLLCKD_DI}	Setup and hold of D input	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{PLLDCK_DEN} /T _{PLLCKD_DEN}	Setup and hold of D enable	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
T _{PLLDCK_DWE} /T _{PLLCKD_DWE}	Setup and hold of D write enable	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{PLLCKO_DRDY}	CLK to out of DRDY	0.65	0.72	0.99	0.99	ns, Max
F _{DCK}	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

Notes:

1. The PLL does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any PLL outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as F_{VCO}/128 assuming output duty cycle is 50%.

GTP Transceiver Specifications

GTP Transceiver DC Input and Output Levels

Table 47 summarizes the DC output specifications of the GTP transceivers in Artix-7 FPGAs. Consult [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) for further details.

Table 47: GTP Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV_{PPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to maximum setting	—	—	1000	mV
$V_{CMOUTDC}$	DC common mode output voltage	Equation based	$V_{MGTAVTT} - DV_{PPOUT}/4$			mV
R_{OUT}	Differential output resistance		—	100	—	Ω
$V_{CMOUTAC}$	Common mode output voltage: AC coupled		$1/2 V_{MGTAVTT}$			mV
T_{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew (FFG, FBG, SBG packages)		—	—	10	ps
	Transmitter output pair (TXP and TXN) intra-pair skew (FGG, FTG, CSG packages)		—	—	12	ps
DV_{PPIN}	Differential peak-to-peak input voltage	External AC coupled	150	—	2000	mV
V_{IN}	Absolute input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	-200	—	$V_{MGTAVTT}$	mV
V_{CMIN}	Common mode input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	—	$2/3 V_{MGTAVTT}$	—	mV
R_{IN}	Differential input resistance		—	100	—	Ω
C_{EXT}	Recommended external AC coupling capacitor ⁽²⁾		—	100	—	nF

Notes:

- The output swing and preemphasis levels are programmable using the attributes discussed in [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) and can result in values lower than reported in this table.
- Other values can be used as appropriate to conform to specific protocols and standards.

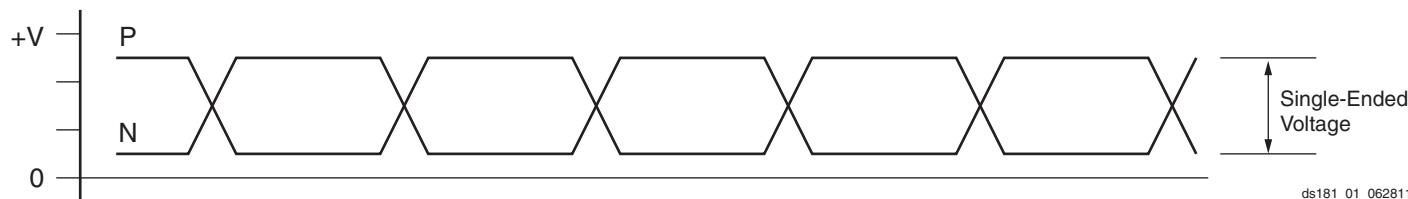


Figure 1: Single-Ended Peak-to-Peak Voltage

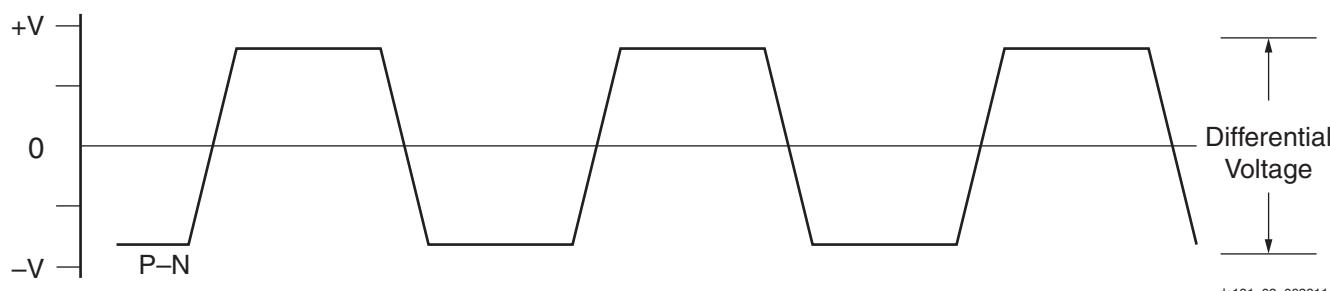


Figure 2: Differential Peak-to-Peak Voltage

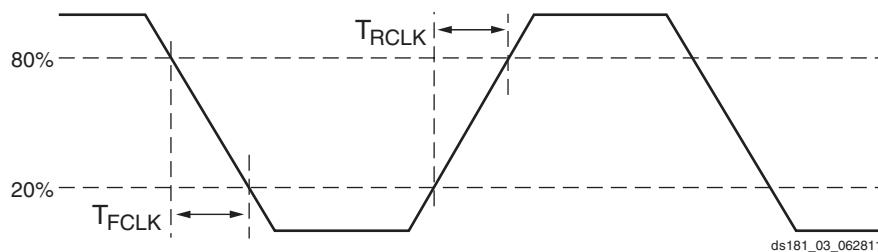


Figure 3: Reference Clock Timing Parameters

Table 52: GTP Transceiver PLL/Lock Time Adaptation

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T _{LOCK}	Initial PLL lock		—	—	1	ms
T _{DLOCK}	Clock recovery phase acquisition and adaptation time.	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	—	50,000	2.3 x 10 ⁶	UI

Table 53: GTP Transceiver User Clock Switching Characteristics⁽¹⁾

Symbol	Description	Conditions	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
F _{TXOUT}	TXOUTCLK maximum frequency		412.500	412.500	234.375	234.375	MHz
F _{RXOUT}	RXOUTCLK maximum frequency		412.500	412.500	234.375	234.375	MHz
F _{TXIN}	TXUSRCLK maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz
F _{RXIN}	RXUSRCLK maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz
F _{TXIN2}	TXUSRCLK2 maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz
F _{RXIN2}	RXUSRCLK2 maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz

Notes:

1. Clocking must be implemented as described in [UG482: 7 Series FPGAs GTP Transceiver User Guide](#).

Table 54: GTP Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F_{GTPTX}	Serial data rate range		0.500	—	F_{GTPMAX}	Gb/s
T_{RTX}	TX rise time	20%–80%	—	50	—	ps
T_{FTX}	TX fall time	20%–80%	—	50	—	ps
T_{LLSKEW}	TX lane-to-lane skew ⁽¹⁾		—	—	500	ps
$V_{TXOOBVDPDPP}$	Electrical idle amplitude		—	—	20	mV
$T_{TXOOBTTRANSITION}$	Electrical idle transition time		—	—	140	ns
$TJ_{6.6}$	Total Jitter ⁽²⁾⁽³⁾	6.6 Gb/s	—	—	0.30	UI
$DJ_{6.6}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.15	UI
$TJ_{5.0}$	Total Jitter ⁽²⁾⁽³⁾	5.0 Gb/s	—	—	0.30	UI
$DJ_{5.0}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.15	UI
$TJ_{4.25}$	Total Jitter ⁽²⁾⁽³⁾	4.25 Gb/s	—	—	0.30	UI
$DJ_{4.25}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.15	UI
$TJ_{3.75}$	Total Jitter ⁽²⁾⁽³⁾	3.75 Gb/s	—	—	0.30	UI
$DJ_{3.75}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.15	UI
$TJ_{3.2}$	Total Jitter ⁽²⁾⁽³⁾	3.20 Gb/s ⁽⁴⁾	—	—	0.2	UI
$DJ_{3.2}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.1	UI
$TJ_{3.2L}$	Total Jitter ⁽²⁾⁽³⁾	3.20 Gb/s ⁽⁵⁾	—	—	0.32	UI
$DJ_{3.2L}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.16	UI
$TJ_{2.5}$	Total Jitter ⁽²⁾⁽³⁾	2.5 Gb/s ⁽⁶⁾	—	—	0.20	UI
$DJ_{2.5}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.08	UI
$TJ_{1.25}$	Total Jitter ⁽²⁾⁽³⁾	1.25 Gb/s ⁽⁷⁾	—	—	0.15	UI
$DJ_{1.25}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.06	UI
TJ_{500}	Total Jitter ⁽²⁾⁽³⁾	500 Mb/s	—	—	0.1	UI
DJ_{500}	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.03	UI

Notes:

1. Using same REFCLK input with TX phase alignment enabled for up to four consecutive transmitters (one fully populated GTP Quad).
2. Using PLL[0/1]_FBDIV = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. All jitter values are based on a bit-error ratio of $1e^{-12}$.
4. PLL frequency at 3.2 GHz and TXOUT_DIV = 2.
5. PLL frequency at 1.6 GHz and TXOUT_DIV = 1.
6. PLL frequency at 2.5 GHz and TXOUT_DIV = 2.
7. PLL frequency at 2.5 GHz and TXOUT_DIV = 4.

Table 62: XADC Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
DCLK Duty Cycle			40	—	60	%
XADC Reference⁽⁵⁾						
External Reference	V _{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V
On-Chip Reference		Ground V _{REFP} pin to AGND, T _j = -40°C to 100°C	1.2375	1.25	1.2625	V

Notes:

- Offset and gain errors are removed by enabling the XADC automatic gain calibration feature. The values are specified for when this feature is enabled.
- Only specified for BitGen option XADCEnhancedLinearity = ON.
- See the ADC chapter in [UG480: 7 Series FPGAs XADC User Guide](#) for a detailed description.
- See the Timing chapter in [UG480: 7 Series FPGAs XADC User Guide](#) for a detailed description.
- Any variation in the reference voltage from the nominal V_{REFP} = 1.25V and V_{REFN} = 0V will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratioimetric type applications allowing reference to vary by ±4% is permitted. On-chip reference variation is ±1%.

Configuration Switching Characteristics

Table 63: Configuration Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Power-up Timing Characteristics						
T _{PL} ⁽¹⁾	Program latency	5.00	5.00	5.00	5.00	ms, Max
T _{POR} ⁽¹⁾	Power-on reset (50 ms ramp rate time)	10/50	10/50	10/50	10/50	ms, Min/Max
	Power-on reset (1 ms ramp rate time)	10/35	10/35	10/35	10/35	ms, Min/Max
T _{PROGRAM}	Program pulse width	250.00	250.00	250.00	250.00	ns, Min
CCLK Output (Master Mode)						
T _{ICCK}	Master CCLK output delay	150.00	150.00	150.00	150.00	ns, Min
T _{MCCKL}	Master CCLK clock Low time duty cycle	40/60	40/60	40/60	40/60	%, Min/Max
T _{MCCKH}	Master CCLK clock High time duty cycle	40/60	40/60	40/60	40/60	%, Min/Max
F _{MCCK}	Master CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
	Master CCLK frequency for AES encrypted x16	50.00	50.00	50.00	35.00	MHz, Max
F _{MCCK_START}	Master CCLK frequency at start of configuration	3.00	3.00	3.00	3.00	MHz, Typ
F _{MCCKTOL}	Frequency tolerance, master mode with respect to nominal CCLK	±50	±50	±50	±50	%, Max
CCLK Input (Slave Modes)						
T _{SCCKL}	Slave CCLK clock minimum Low time	2.50	2.50	2.50	2.50	ns, Min
T _{SCCKH}	Slave CCLK clock minimum High time	2.50	2.50	2.50	2.50	ns, Min
F _{SCCK}	Slave CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
EMCCLK Input (Master Mode)						
T _{EMCCKL}	External master CCLK Low time	2.50	2.50	2.50	2.50	ns, Min
T _{EMCCKH}	External master CCLK High time	2.50	2.50	2.50	2.50	ns, Min
F _{EMCCK}	External master CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max

Revision History

The following table shows the revision history for this document:

Date	Version	Description
09/26/11	1.0	Initial Xilinx release.
11/07/11	1.1	Revised the V_{OCM} specification in Table 11 . Updated the AC Switching Characteristics based upon the ISE 13.3 software v1.02 speed specification throughout document including Table 12 and Table 13 . Added $MMCM_T_{FBDELAY}$ while adding $MMCM_$ to the symbol names of a few specifications in Table 34 and PLL to the symbol names in Table 35 . In Table 36 through Table 43 , updated the pin-to-pin description with the SSTL15 standard. Updated units in Table 46 .
02/13/12	1.2	Updated the Artix-7 family of devices listed throughout the entire data sheet. Updated the AC Switching Characteristics based upon the ISE 13.4 software v1.03 for the -3, -2, and -1 speed grades and v1.00 for the -2L speed grade. Updated summary description on page 1 . In Table 2 , revised V_{CCO} for the 3.3V HR I/O banks and updated T_j . Updated the notes in Table 5 . Added MGTAVCC and MGTAVTT power supply ramp times to Table 7 . Rearranged Table 8 , added Mobile_DDR, HSTL_I_18, HSTL_II_18, HSUL_12, SSTL135_R, SSTL15_R, and SSTL12 and removed DIFF_SSTL135, DIFF_SSTL18_I, DIFF_SSTL18_II, DIFF_HSTL_I, and DIFF_HSTL_II. Added Table 9 and Table 10 . Revised the specifications in Table 11 . Revised V_{IN} in Table 47 . Updated the eFUSE Programming Conditions section and removed the endurance table. Added the table . Revised F_{TXIN} and F_{RXIN} in Table 53 . Revised I_{CCADC} and updated Note 1 in Table 62 . Revised DDR LVDS transmitter data width in Table 14 . Removed notes from Table 24 as they are no longer applicable. Updated specifications in Table 63 . Updated Note 1 in Table 33 .
06/01/12	1.3	Reorganized entire data sheet including adding Table 40 and Table 44 . Updated T_{SOL} in Table 1 . Updated I_{BATT} and added R_{IN_TERM} to Table 3 . Updated Power-On/Off Power Supply Sequencing section with regards to GTP transceivers. In Table 8 , updated many parameters including SSTL135 and SSTL135_R. Removed V_{OX} column and added DIFF_HSUL_12 to Table 10 . Updated V_{OL} in Table 11 . Updated Table 14 and removed notes 2 and 3. Updated Table 15 . Updated the AC Switching Characteristics based upon the ISE 14.1 software v1.03 for the -3, -2, -2L (1.0V), -1, and v1.01 for the -2L (0.9V) speed specifications throughout the document. In Table 27 , updated Reset Delays section including Note 10 and Note 11 . In Table 53 , replaced F_{TXOUT} with F_{GLK} . Updated many of the XADC specifications in Table 62 and added Note 2 . Updated and moved <i>Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK</i> section from Table 63 to Table 34 and Table 35 .

Date	Version	Description
09/20/12	1.4	<p>In Table 1, updated the descriptions, changed V_{IN} and Note 2, and added Note 4. In Table 2, changed descriptions and notes. Updated parameters in Table 3. Added Table 4. Revised the Power-On/Off Power Supply Sequencing section. Updated standards and specifications in Table 8, Table 9, and Table 10. Removed the XC7A350T device from data sheet.</p> <p>Updated the AC Switching Characteristics section to the ISE 14.2 speed specifications throughout the document. Updated the IOB Pad Input/Output/3-State discussion and changed Table 17 by adding $T_{IOIBUFDISABLE}$. Removed many of the combinatorial delay specifications and T_{CINCK}/T_{CKCIN} from Table 24. Changed F_{PFDMAX} conditions in Table 34 and Table 35. Updated the GTP Transceiver Specifications section, moved the GTP Transceiver DC characteristics section to the overall DC Characteristics section, and added the GTP Transceiver Protocol Jitter Characteristics section. In Table 62, updated Note 1. In Table 63, updated T_{POR}.</p>
02/01/13	1.5	<p>Updated the AC Switching Characteristics based upon the 14.4/2012.4 device pack for ISE 14.4 and Vivado 2012.4, both at v1.07 for the -3, -2, -2L (1.0V), -1 speed specifications, and v1.05 for the -2L (0.9V) speed specifications throughout the document. Production changes to Table 12 and Table 13 for -3, -2, -2L (1.0V), -1 speed specifications.</p> <p>Revised I_{DCIN} and I_{DCOUT} and added Note 5 in Table 1. Added Note 2 to Table 2. Updated Table 5. Added minimum current specifications to Table 6. Removed SSTL12 and HSTL_I_12 from Table 8. Removed DIFF_SSTL12 from Table 10. Updated Table 12. Added a 2:1 memory controller section to Table 15. Updated Note 1 in Table 31. Revised Table 33. Updated Note 1 and Note 2 in Table 46. Updated D_{VPPI} in Table 47. Updated V_{IDIFF} in Table 48. Removed T_{LOCK} and T_{PHASE} and revised F_{GCLK} in Table 51. Updated T_{DLOCK} in Table 52. Updated Table 53. In Table 54, updated T_{RTX}, T_{FTX}, $V_{TXOOBVDDPP}$, and revised Note 1 through Note 7. In Table 55, updated RX_{SST} and RX_{PPMTOL} and revised Note 4 through Note 7. In Table 60, revised and added Note 1.</p> <p>Revised the maximum external channel input ranges in Table 62. In Table 63, revised F_{MCCK} and added the Internal Configuration Access Port section.</p>